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## NTE6507 Integrated Circuit NMOS, 8 Bit Microprocessor (MPU) w/On-Chip Clock OSC

**Description:**

The NTE6507 integrated circuit is an 8 bit microprocessor in a 28-Lead DIP type package which provides a selection of addressable memory range, interrupt input options, and on-chip clock oscillators and drivers. This device is bus compatible with the MC6800 product offering and is aimed at high performance, low cost applications where single phase inputs or crystals provide the time base.

**Features:**

- Single 5V ±5% Power Supply
- N Channel, Silicon Gate, Depletion Load Technology
- 8 Bit Parallel Processing
- Decimal and Binary Arithmetic
- Thirteen Addressing Modes
- True Indexing Capability
- Programmable Stack Pointer
- Variable Length Stack
- Bi-Directional Data Bus
- Instruction Decoding and Control
- 8k Addressable Bytes of Memory
- "Ready" Input
- Direct Memory Access Capability
- Bus Compatible with MC6800
- On-Board Clock
- 1MHz Operating Frequency

**Absolute Maximum Ratings:** (Note 1)

Supply Voltage, $V_{CC}$ .....	-0.3 to +7.0V
Input Voltage, $V_{in}$ .....	-0.3 to +7.0V
Operating Temperature Range, $T_A$ .....	0 to +70°C
Storage Temperature Range, $T_{stg}$ .....	-55° to +150°C

Note 1. This device contains input protection against damage due to high static voltages or electric fields; however, precautions should be taken to avoid application of voltages higher than the maximum rating.

**DC Characteristics:** ( $V_{CC} = 5V \pm 5\%$ ,  $T_A = 0^\circ$  to  $+70^\circ C$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Max	Unit
Input High Voltage Logic and $\phi_{o(in)}$	$V_{IH}$		+2.0	$V_{CC}$	V
Logic			$V_{CC}-0.5$	$V_{CC}+0.25$	V
Input Low Voltage Logic and $\phi_{o(in)}$	$V_{IL}$		-0.3	+0.8	V
Input Loading RDY	$I_{IL}$	$V_{in} = 0V$ , $V_{CC} = 5.25V$	-10	-300	$\mu A$
Input Leakage Current Logic (Excluding RDY)	$I_{in}$	$V_{in} = 0$ to $5.25V$ , $V_{CC} = 0$	-	2.5	$\mu A$
$\phi_{o(in)}$			-	10.0	$\mu A$
Three-State (Off State) Input Current DB0-DB7	$I_{TSI}$	$V_{in} = 0.4$ to $2.4V$ , $V_{CC} = 5.25V$	-	$\pm 10$	$\mu A$
Output High Voltage DB0-DB7, A0-A15, $R/\bar{W}$	$V_{OH}$	$I_{LOAD} = -100\mu A$ , $V_{CC} = 4.75V$	2.4	-	V
Output Low Voltage DB0-DB7, A0-A15, $R/\bar{W}$	$V_{OL}$	$I_{LOAD} = 1.6mA$ , $V_{CC} = 4.75V$	-	0.4	V
Power Dissipation	$P_D$	$V_{CC} = 5.25V$	-	700	mW
Capacitance RES, RDY,	$C_{in}$	$V_{in} = 0$ , $T_A = +25^\circ C$ , $f = 1MHz$	-	10	pF
DB0-DB7			-	15	pF
A0-A15, $R/\bar{W}$	$C_{out}$		-	12	pF
$\phi_{o(in)}$	$C_{\phi_{o(in)}}$		-	15	pF

**Dynamic Operating Characteristics:** ( $V_{CC} = 5V \pm 5\%$ ,  $T_A = 0^\circ$  to  $+70^\circ C$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Max	Unit
Cycle Time	$T_{CYC}$		1.00	40	$\mu s$
$\phi_{o(in)}$ Low Time	$T_{L\phi_0}$	Note 2	480	-	ns
$\phi_{o(in)}$ High Time	$T_{H\phi_0}$	Note 2	460	-	ns
$\phi_0$ Neg to $\phi_1$ Pos Delay	$T_{01+}$	Load = 100pF	10	70	ns
$\phi_0$ Neg to $\phi_2$ Neg Delay	$T_{02-}$	Load = 100pF	5	65	ns
$\phi_0$ Pos to $\phi_1$ Neg Delay	$T_{01-}$	Load = 100pF	5	65	ns
$\phi_0$ Pos to $\phi_2$ Pos Delay	$T_{02+}$	Load = 100pF	15	75	ns
$\phi_{\alpha(in)}$ Rise and Fall Time	$T_{RO}$ , $T_{FO}$	Note 3	0	30	ns
$\phi_1(OUT)$ Pulse Width	$T_{PWH\phi_1}$		$T_{L\phi_0}-20$	$T_{L\phi_0}$	ns
$\phi_2(OUT)$ Pulse Width	$T_{PWH\phi_2}$		$T_{L\phi_0}-40$	$T_{L\phi_0}-10$	ns
Delay Between $\phi_1$ and $\phi_2$	$T_D$		5	-	ns
$\phi_1$ and $\phi_2$ Rise and Fall Times	$T_R$ , $T_F$	Load = 1TTL load +30pF, Note 3	-	25	ns

Note 2. Measured at 50% points.

Note 3. Measured between 10% and 90% points.

**Dynamic Operating Characteristics (Cont'd):** ( $V_{CC} = 5V \pm 5\%$ ,  $T_A = 0$  to  $+70^\circ C$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Max	Unit
R/W Setup Time	$T_{RWS}$		–	225	ns
R/W Hold Time	$T_{RWH}$		30	–	ns
Address Setup Time	$T_{ADS}$		–	225	ns
Address Hold Time	$T_{ADH}$		30	–	ns
Read Access Time	$T_{ACC}$		–	650	ns
Read Data Setup Time	$T_{DSU}$		100	–	ns
Read Data Hold Time	$T_{HR}$		10	–	ns
Write Data Setup Time	$T_{MDS}$		20	175	ns
Write Data Hold Time	$T_{HW}$		60	150	ns
Sync Setup Time	$T_{SYS}$		–	350	ns
Sync Hold Time	$T_{SYH}$		30	–	ns
RDY Setup Time	$T_{RS}$	Note 4	200	–	ns

Note 4. RDY must never switch states within  $T_{RS}$  to end of  $\emptyset_2$ .



